TOSHIBA Photocoupler GaAlAs Ired & Photo IC

6N138, 6N139

Current Loop Driver.

Low Input Current Line Receiver.

CMOS Logic Interface.

The TOSHIBA 6N138 and 6N139 consists of a GaAlAs infrared

emitting diode coupled with a split-Darlington output configuration.

A high speed GaAlAs Ired manufactured with an unique LPE junction, has the virtue of fast rise and fall time at low drive current.

- Isolation voltage: 2500Vrms (min.)
- Current transfer ratio

: 6N138 - 300% (min.) (I_F=1.6mA)

: 6N139 - 400% (min.) (I_F=0.5mA)

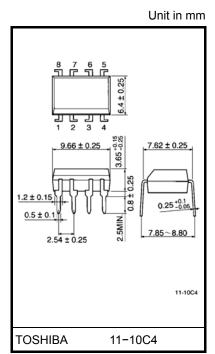
• Switching time: 6N138 - tPHL=10µs (max.)

- t_{PLH}=35μs (max.)

 $6N139 - t_{PHL} = 1 \mu s (max.)$

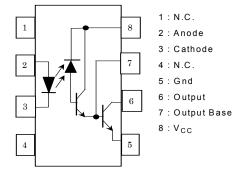
- tpLH=7 μs (max.)

• UL recognized: UL1577, file no. E67349

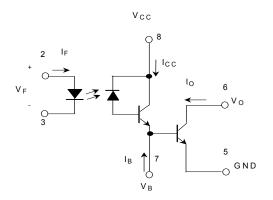


Weight: 0.54 g (typ.)

Pin Configuration (top view)



Schematic



Absolute Maximum Ratings (*) (Ta = 0°C to + 70°C)

	Characteristic	Symbol	Rating	Unit	
LED	Forward current	(Note 1)	lF	20	mA
	Pulse forward current	current		40	mA
	otal pulse forward current		IFP ^(*2)	1	А
	Reverse voltage		V _R	5	V
	Diode power dissipation	(Note 2)	P _D	35	mW
	Output current	(Note 3)	IO	60	mA
Detector	Emitter-base reverse voltage		V _{EB}	0.5	V
	Supply voltage		V _{CC} ^(*3)	–0.5 to 18	V
۵	Output voltage		VO ^(*3)	–0.5 to 18	V
	Output power dissipation	(Note 4)	PO	100	mW
Оре	Operating temperature range		T _{opr}	0 to 70	°C
Sto	Storage temperature range		T _{stg}	-55 to 125	°C
Lea	Lead solder temperature (10s) (*4)		T _{sol}	260	°C
leel	Inclation voltage (4min DIL < 600/)		BV _S ^(**)	2500	V _{rms}
Isolation voltage (1min., R.H.≤ 60%)		DAZ	3540	V _{dc}	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

- (*) JEDEC registered data
- (**) Not registered JEDEC
- (*1) 50% duty cycle, 1ms pulse width
- (*2) Pulse width 1µs, 300pps
- (*3) $6N138 \cdots -0.5$ to 7V
- (*4) 1.6mm below seating plane

Electrical Characteristics Over Recommended Temperature (Ta = 0°C to 70°C, unless otherwise noted)

Characteristic		Symbol	Test Condition	Min.	(*5)Typ.	Max.	Unit
Current transfer	6N139	CTR(*)	I _F =0.5mA, V _O =0.4V V _{CC} =4.5V	400	800	_	. %
ratio (Note 5, 6)			I _F =1.6mA, V _O =0.4V V _{CC} =4.5V	500	900	_	
	6N138			300	600		
	6N139	V _{OL}	I _F =1.6mA, I _O =6.4mA V _{CC} =4.5V	_	0.1	0.4	. V
Logic low output			I _F =5mA, I _O =15mA V _{CC} =4.5V	_	0.1	0.4	
voltage (Note 6)			I _F =12mA, I _O =24mA V _{CC} =4.5V	_	0.2	0.4	
	6N138		I _F =1.6mA, I _O =4.8mA V _{CC} =4.5V	_	0.1	0.4	
Logic high output	6N139	I _{OH} (*)	I _F =0mA, V _O =V _{CC} =18V	_	0.05	100	μΑ
current (Note 6)	6N138		I _F =0mA, V _O =V _{CC} =7V	_	0.05	250	
Logic low supply current	(Note 6)	ICCL	I _F =1.6mA, V _O =Open V _{CC} =5V	_	0.2	_	mA
Logic high supply current	(Note 6)	Іссн	I _F =0mA, V _O =Open, V _{CC} =5V	_	10	_	nA
Input forward voltage		V _F (*)	I _F =1.6mA, Ta=25°C	_	1.65	1.7	V
Input reverse breakdown voltage		BV _R (*)	I _R =10μA, Ta=25°C	5	_	_	V
Temperature coefficient of forward voltage		ΔV _F / ΔTa	I _F =1.6mA	_	-1.9	_	mV / °C
Input capacitance		C _{IN}	f=1MHz, V _F =0	_	60	_	pF
Resistance (input-output)		R _{I-O}	V _{I-O} =500V (Note 7), R.H.≤ 60%	_	10 ¹²	_	Ω
Capacitance (input-output)		C _{I-O}	f=1MHz (Note 7)	_	0.6	_	pF

^(**) JEDEC registered data.

^(*5) All typicals at Ta=25°C and V_{CC}=5V, unless otherwise noted.

Switching Specifications (Ta=25°C, V_{CC}=5V, unless otherwise specified)

Characteristic		Symbol	Test Circuit	Test Condition	Min.	Тур.	Max.	Unit
Propagation delay	6N139	t _{pHL} (*)	1	I_F =0.5mA, R_L =4.7k Ω	_	5	25	μs
time to logic low				I _F =12mA, R _L =270Ω	_	0.2	1	
at output (Note 6, 8)	6N138			I _F =1.6mA, R _L =2.2kΩ	_	1	10	
Propagation delay	6N139		1	I_F =0.5mA, R_L =4.7k Ω	_	5	60	μs
time to logic high	t _{pLH} (*)	t _{pLH} (*)		I_F =12mA, R_L =270 Ω	_	1	7	
at output (Note 6, 8)	6N138			I _F =1.6mA, R _L =2.2kΩ	_	4	35	
Common mode transient immunity at logic high level output	(Note 9)	CM _H	2	I_F =0mA, R_L =2.2k Ω V_{CM} =400 V_{p-p}	_	500	_	V / μs
Common mode transient immunity at logic low level output	(Note 9)	CML	2	$I_{\text{F}}\text{=}1.6\text{mA}$ $R_{\text{L}}\text{=}2.2\text{k}\Omega$ $V_{\text{CM}}\text{=}400V_{p-p}$		-500		V / μs

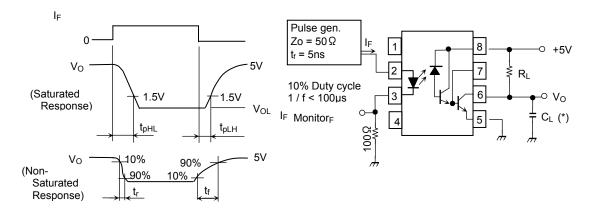
(*)JEDEC registered data.

- (Note 1): Derate linearly above 50°C free-air temperature at a rate of 0.4mA / °C
- (Note 2): Derate linearly above 50°C free-air temperature at a rate of 0.7mW / °C
- (Note 3): Derate linearly above 25°C free-air temperature at a rate of 0.7mA / °C
- (Note 4): Derate linearly above 25°C free-air temperature at a rate of 2.0mW / °C
- (Note 5): DC CURRENT TRANSFER RATIO is defined as the ratio of output collector current, I_O, to the forward LED input current, I_F, times 100%.
- (Note 6): Pin 7 open.
- (Note 7): Device considered a two–terminal device: Pins 1, 2, 3, and 4 shorted together and Pins 5, 6, 7 and 8 shorted together.
- (Note 8): Use of a resistor between pin 5 and 7 will decrease gain and delay time.
- (Note 9): Common mode transient immunity in logic high level is the maximum tolerable (positive) dv_{CM} / dt on the leading edge of the common mode pulse, V_{CM} , to assure that the output will remain in a logic high state (i.e., $V_{CM} > 2.0V$).

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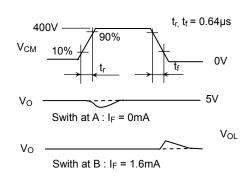
Common mode transient immunity in Logic Low level is the maximum tolerable (negative) dv_{CM} / dt on the trailing edge of the common mode pulse signal, V_{CM} , to assure that the output will remain in a logic low state (i.e., $V_O < 0.8V$).

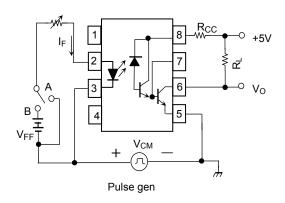
Test Circuit 1.



(*) $C_{\rm L}$ is approximately 15pF which includes probe and stray wiring capacitance.

Test Circuit 2.





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